

Search Notes

Application/Control No.

10/507,152

Examiner

Richard Edgar

Applicant(s)/Patent under
Reexamination

BEYER ET AL.

Art Unit

3745

SEARCHED

| Class | Subclass | Date | Examiner |
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| 415 | 73 90 | 2/15/2006 | RE |
| 416 | 176 | 2/15/2006 | RE |
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INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

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| STIC PLUS Search | 2/15/2006 | RE |
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